



FAST CMOS 1-OF-4 DECODER WITH ENABLE

IDT54/74FCT139T/AT/CT

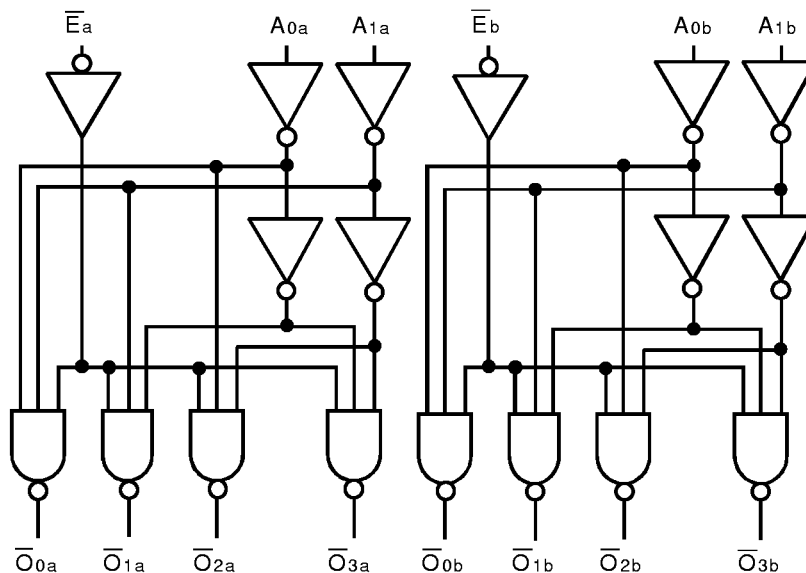
FEATURES:

- Std., A and C speed grades
- Low input and output leakage $\leq 1\mu\text{A}$ (max.)
- Extended commercial range of -40°C to $+85^\circ\text{C}$
- CMOS power levels
- True TTL input and output compatibility
 - $V_{OH} = 3.3\text{V}$ (typ.)
 - $V_{OL} = 0.3\text{V}$ (typ.)
- High drive outputs (-15mA I_{OH} , 48mA I_{OL})
- Meets or exceeds JEDEC standard 18 specifications
- Product available in Radiation Tolerant and Radiation Enhanced versions
- Military product compliant to MIL-STD-883, Class B and DESC listed (dual marked)
- Available in DIP, SOIC, QSOP, CERPACK and LCC packages

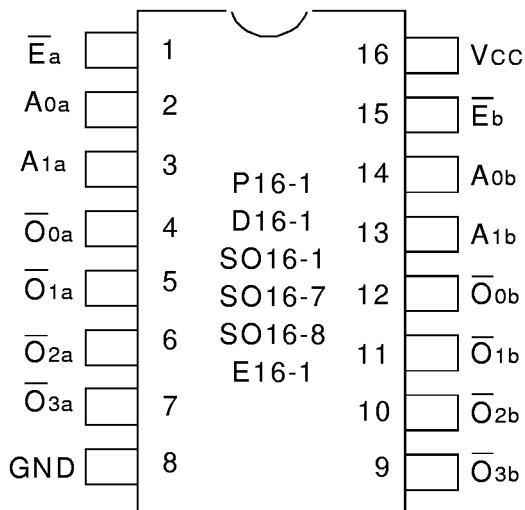
DESCRIPTION:

The IDT54/74FCT139T/AT/CT are dual 1-of-4 decoders built using an advanced dual metal CMOS technology. These devices have two independent decoders, each of which accept two binary weighted inputs (A_0 - A_1) and provide four mutually exclusive active low outputs (\bar{O}_0 - \bar{O}_3). Each decoder has an active low enable (\bar{E}). When \bar{E} is high, all outputs are forced high.

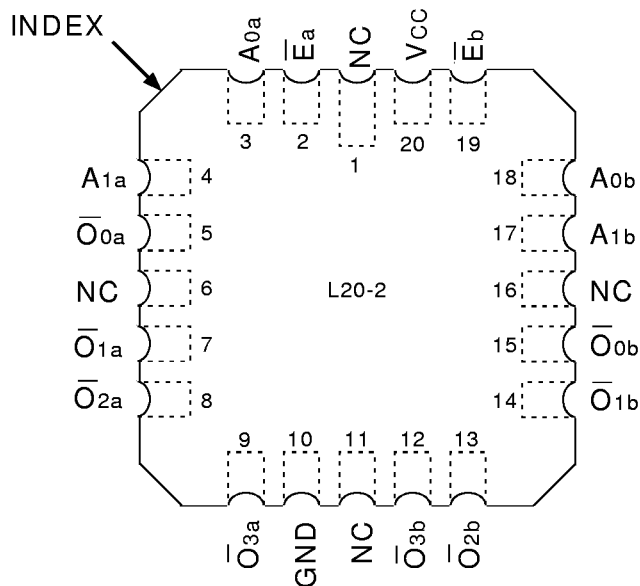
FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATION



DIP/ SOIC/ QSOP/ CERPACK
TOP VIEW



LCC
TOP VIEW

ABSOLUTE MAXIMUM RATINGS(1)

Symbol	Rating	Max.	Unit
V _{TERM} (2)	Terminal Voltage with Respect to GND	-0.5 to +7	V
V _{TERM} (3)	Terminal Voltage with Respect to GND	-0.5 to V _{CC} +0.5	V
T _{STG}	Storage Temperature	-65 to +150	°C
I _{OUT}	DC Output Current	-65 to +120	mA

8T-sink

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed V_{CC} by +0.5V unless otherwise noted.
- Inputs and V_{CC} terminals only.
- Outputs and I/O terminals only.

CAPACITANCE (T_A = +25°C, f = 1.0MHz)

Symbol	Parameter(1)	Conditions	Typ.	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	6	10	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0V	8	12	pF

8T-sink

NOTE:

- This parameter is measured at characterization but not tested.

PIN DESCRIPTION

Pin Names	Description
A ₀ , A ₁	Address Inputs
\bar{E}	Enable Input (Active LOW)
$\bar{O}_0 - \bar{O}_3$	Outputs (Active LOW)

FUNCTION TABLE (1)

Inputs			Outputs			
\bar{E}	A ₀	A ₁	\bar{O}_0	\bar{O}_1	\bar{O}_2	\bar{O}_3
H	X	X	H	H	H	H
L	L	L	L	H	H	H
L	H	L	H	L	H	H
L	L	H	H	H	L	H
L	H	H	H	H	H	L

NOTE:

- H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Commercial: $T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$, $V_{CC} = 5.0\text{V} \pm 5\%$; Military: $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$, $V_{CC} = 5.0\text{V} \pm 10\%$

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
V_{IH}	Input HIGH Level	Guaranteed Logic HIGH Level		2	—	—	V
V_{IL}	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
I_{IH}	Input HIGH Current ⁽⁴⁾	$V_{CC} = \text{Max.}$	$V_I = 2.7\text{V}$	—	—	± 1	μA
I_{IL}	Input LOW Current ⁽⁴⁾	$V_{CC} = \text{Max.}$	$V_I = 0.5\text{V}$	—	—	± 1	μA
I_I	Input HIGH Current ⁽⁴⁾	$V_{CC} = \text{Max.}, V_I = V_{CC} (\text{Max.})$		—	—	± 1	μA
V_{IK}	Clamp Diode Voltage	$V_{CC} = \text{Min.}, I_N = -18\text{mA}$		—	-0.7	-1.2	V
I_{OS}	Short Circuit Current	$V_{CC} = \text{Max.}^{(3)}, V_O = \text{GND}$		-60	-120	-225	mA
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -6\text{mA MIL}$ $I_{OH} = -8\text{mA COM'L}$	2.4	3.3	—	V
			$I_{OH} = -12\text{mA MIL}$ $I_{OH} = -15\text{mA COM'L}$	2	3	—	V
V_{OL}	Output LOW Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 32\text{mA MIL}$ $I_{OL} = 48\text{mA COM'L}$	—	0.3	0.5	V
V_H	Input Hysteresis	—		—	200	—	mV
I_{CC}	Quiescent Power Supply Current	$V_{CC} = \text{Max.}$ $V_{IN} = \text{GND}$ or V_{CC}		—	0.01	1	mA

NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0\text{V}$, $+25^\circ\text{C}$ ambient and maximum loading.
- Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.
- The test limit for this parameter is $\pm 5\mu\text{A}$ at $T_A = -55^\circ\text{C}$.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$		—	0.5	2	mA
I_{CCD}	Dynamic Power Supply Current ⁽⁴⁾	$V_{CC} = \text{Max.}$ Outputs Open One Bit Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	0.15	0.3	mA/ MHz
I_C	Total Power Supply Current ⁽⁶⁾	$V_{CC} = \text{Max.}$ Outputs Open $f_o = 10\text{MHz}$ 50% Duty Cycle One Input and One Output Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	1.5	4	mA
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	1.8	5	
		$V_{CC} = \text{Max.}$ Outputs Open $f_o = 10\text{MHz}$ 50% Duty Cycle One Input Toggling on Each Decoder Two Outputs Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	3	7 ⁽⁵⁾	
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	3.5	9 ⁽⁵⁾	

NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0V$, $+25^\circ\text{C}$ ambient.
- Per TTL driven input ($V_{IN} = 3.4V$). All other inputs at V_{CC} or GND .
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $I_C = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$
 $I_C = I_{CC} + \Delta I_{CC} \text{DH}_{NT} + I_{CCD} (f_o \text{No})$
 $I_{CC} = \text{Quiescent Current}$
 $\Delta I_{CC} = \text{Power Supply Current for a TTL High Input } (V_{IN} = 3.4V)$
 $\text{DH} = \text{Duty Cycle for TTL Inputs High}$
 $\text{NT} = \text{Number of TTL Inputs at DH}$
 $I_{CCD} = \text{Dynamic Current Caused by an Input Transition Pair (HLH or LHL)}$
 $f_o = \text{Output Frequency}$
 $\text{No} = \text{Number of Outputs at } f_o$
 All currents are in milliamps and all frequencies are in megahertz.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

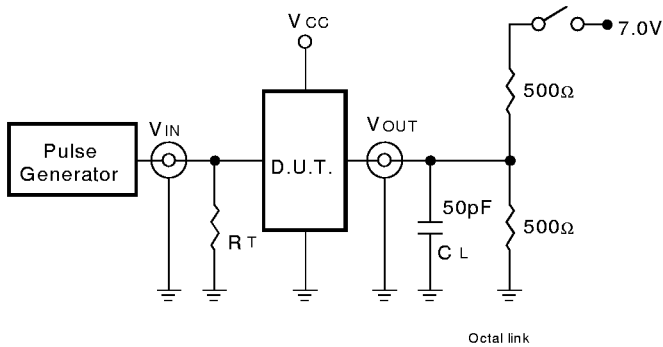
Parameter	Description	Condition ⁽¹⁾	FCT139T		FCT139AT				FCT139CT				Unit		
			Com'l.		Mil.		Com'l.		Mil.		Com'l.			Mil.	
			Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.		Min. ⁽²⁾	Max.
t_{PLH}	Propagation Delay	$C_L = 50\text{pF}$ $R_L = 500\Omega$	1.5	9	1.5	12	1.5	5.9	1.5	7.8	1.5	5	1.5	6.2	ns
t_{PHL}	A_0 or A_1 to \bar{O}_n														
t_{PLH}	Propagation Delay	\bar{E} to \bar{O}_n	1.5	8	1.5	9	1.5	5.5	1.5	7.2	1.5	4.8	1.5	5.8	ns
t_{PHL}															

NOTES:

- See test circuit and waveforms.
- Minimum limits are guaranteed but not tested on Propagation Delays.

TEST CIRCUITS AND WAVEFORMS

TEST CIRCUITS FOR ALL OUTPUTS



SWITCH POSITION

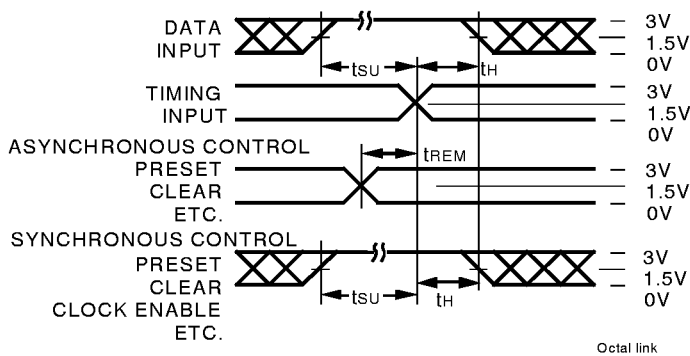
Test	Switch
Open Drain	Closed
Disable Low	
Enable Low	
All Other Tests	Open

DEFINITIONS:

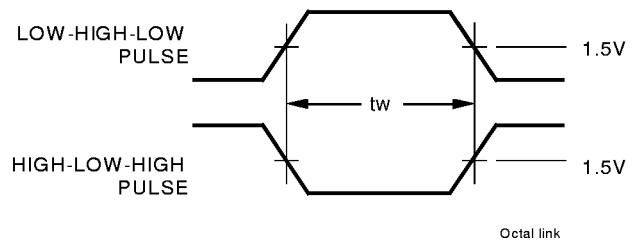
CL = Load capacitance: includes jig and probe capacitance.

RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.

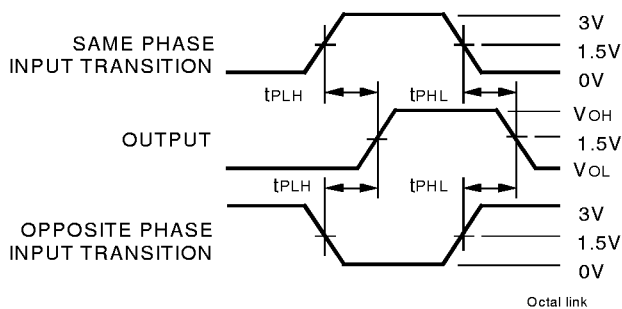
SET-UP, HOLD, AND RELEASE TIMES



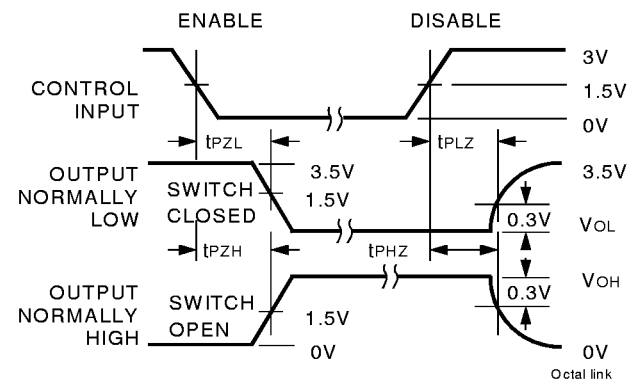
PULSE WIDTH



PROPAGATION DELAY



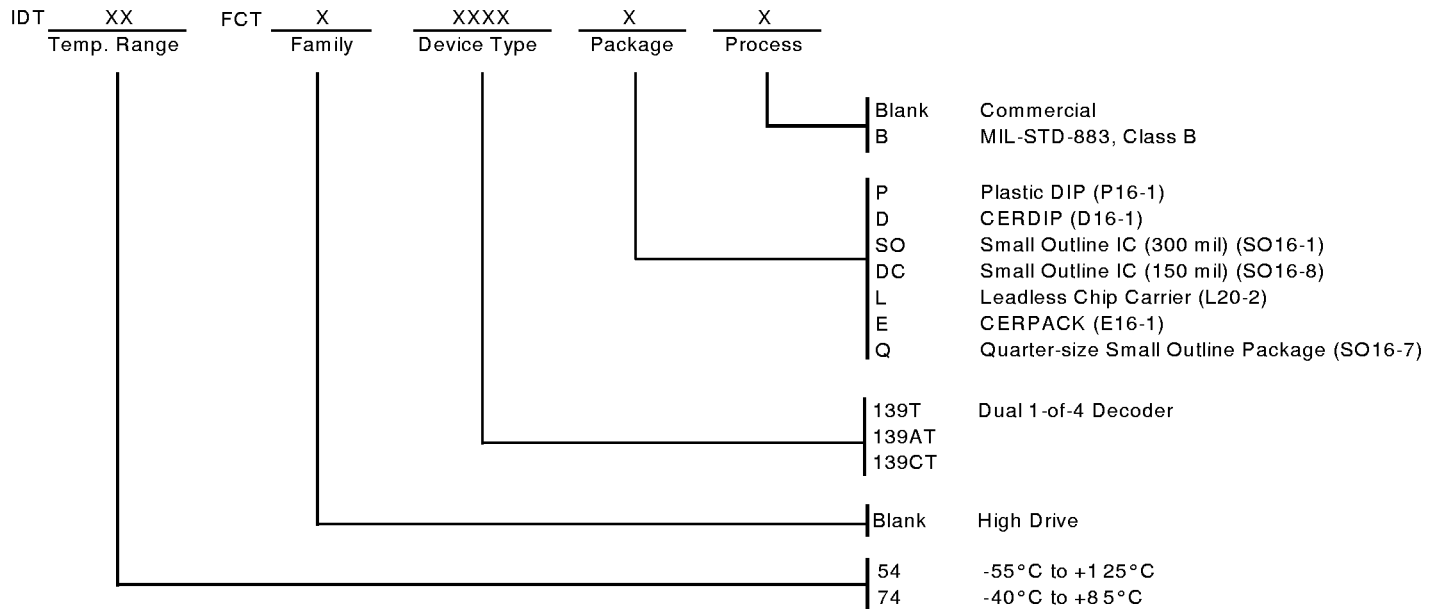
ENABLE AND DISABLE TIMES



NOTES:

- Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
- Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_f \leq 2.5\text{ns}$; $t_r \leq 2.5\text{ns}$

ORDERING INFORMATION



CORPORATE HEADQUARTERS
 2975 Stender Way
 Santa Clara, CA 95054

for SALES:
 800-345-7015 or 408-727-6116
 fax: 408-492-8674
www.idt.com*

*To search for sales office near you, please click the sales button found on our home page or dial the 800# above and press 2.
 The IDT logo is a registered trademark of Integrated Device Technology, Inc.